

<b>Notice of References Cited</b>	Application/Control No. 10/520,439		Applicant(s)/Patent Under Reexamination MAYES ET AL.	
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#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
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#### FOREIGN PATENT DOCUMENTS

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#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
	U	Gopal et al. "Electrochemical Capacitance Voltage Profiling of the Narrow Band Gap Semiconductor InAs, " Journal of Electronic Materials, vol. 29, No. 11, 2000			
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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